

1 [0081]

ABSTRACT OF THE DISCLOSURE

2 [0082] The present disclosure pertains to a method of preparing a test specimen for testing
3 of the bonding strength of a layer of additive material to a crystalline substrate, or testing of the
4 bonding strength of one layer of additive material to a second layer of additive material, where
5 both layers of additive material overlie a crystalline substrate. The method includes both test
6 specimen "cutting" from a large sample of material and preparation of an individual test
7 specimen for four-point adhesion testing. Also described is a fixture which is useful for
8 cutting the individual test specimen from the large sample of material.